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PLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION N
10/036,389	01/07/2002	Cheng-Yi Liu	2207/12660	3651
21186	7590 02/18/2004		EXAM	INER
	IAN, LUNDBERG, WO	TRAN, MAI HUONG C		
P.O. BOX 2938 MINNEAPOLIS, MN 55402			ART UNIT	PAPER NUMBER
			2818	

DATE MAILED: 02/18/2004

Please find below and/or attached an Office communication concerning this application or proceeding.

	Applicati n No.	Applicant(s)			
	10/036,389	LIU ET AL.			
Office Action Summary	Examiner	Art Unit			
	Mai-Huong Tran	2818			
The MAILING DATE of this communication Period for Reply	n appears on the cover sheet wi	th the correspondence address			
A SHORTENED STATUTORY PERIOD FOR R THE MAILING DATE OF THIS COMMUNICAT - Extensions of time may be available under the provisions of 37 Of after SIX (6) MONTHS from the mailing date of this communication of the period for reply specified above is less than thirty (30) days of the second for reply is specified above, the maximum statutory of Failure to reply within the set or extended period for reply will, by Any reply received by the Office later than three months after the earned patent term adjustment. See 37 CFR 1.704(b).	ION. FR 1.136(a). In no event, however, may a re on. , a reply within the statutory minimum of thirt period will apply and will expire SIX (6) MON statute, cause the application to become AB	eply be timely filed (30) days will be considered timely. THS from the mailing date of this communication. ANDONED (35 U.S.C. § 133).			
Status					
1)⊠ Responsive to communication(s) filed on	20 January 2004.				
2a) ☐ This action is FINAL . 2b) ☑	This action is non-final.				
* *					
Disposition of Claims					
4) ⊠ Claim(s) 13-27 and 29-44 is/are pending 4a) Of the above claim(s) is/are wit 5) □ Claim(s) is/are allowed. 6) ⊠ Claim(s) 13-27 and 29-44 is/are rejected. 7) □ Claim(s) is/are objected to. 8) □ Claim(s) are subject to restriction and contents.	thdrawn from consideration.				
Application Papers					
9)☐ The specification is objected to by the Exa	aminer.	•			
10)☐ The drawing(s) filed on is/are: a)☐ accepted or b)☐ objected to by the Examiner.					
Applicant may not request that any objection t	- · ·				
Replacement drawing sheet(s) including the country. The oath or declaration is objected to by the country is a second se	•				
Priority under 35 U.S.C. § 119					
12) Acknowledgment is made of a claim for for a) All b) Some * c) None of: 1. Certified copies of the priority docu 2. Certified copies of the priority docu 3. Copies of the certified copies of the application from the International B * See the attached detailed Office action for	ments have been received. ments have been received in A e priority documents have been sureau (PCT Rule 17.2(a)).	pplication No received in this National Stage			
Attachment(s) 1) Notice of References Cited (PTO-892)	4) ☐ Interview S	ummary (PTO-413)			
2) Notice of Draftsperson's Patent Drawing Review (PTO-94	Paper No(s)/Mail Date			
Information Disclosure Statement(s) (PTO-1449 or PTO/S Paper No(s)/Mail Date	5) Notice of Ir 6) Other:	formal Patent Application (PTO-152) ·			

DETAILED ACTION

Claim Rejections - 35 U.S.C. § 103

The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

(a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.

Claims 13-27 and 29-44 are rejected under 35 U.S.C. 103 (a) as being unpatentable over U.S Patent No. 6,672,947 to Tsao et al. in view of Kutlu (6,472,762).

Regarding to claim 13, Tsao discloses a method of fabricating an integrated circuit package, comprising mounting a thinned semiconductor die 4 and a heat sink 12 may be required on top of the thinned die as set forth in col. 3 lines 55-60, col. 5, lines 1-3, lines 43-46, and fig. 2.

Tsao does not disclose mounting a thinned semiconductor die on a planar surface of a heat spreader.

However, Kutlu teaches mounting a thinned semiconductor die on a planar surface of a heat spreader as set forth in col. 3 lines 15-47 and fig. 2.

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It would have been obvious to one of ordinary skill in the art at the time the invention was made to form a thinned semiconductor die on a planar surface of a heat spreader in order to reduce or eliminate die cracks (col. 2, line 14).

Claim 14 is rejected under the same rationale set forth above to claim 13.

Claim 15 is rejected under the same rationale set forth above to claim 13.

Regarding to claim 16, the method wherein the die has a thickness of no more than 100 µm (col. 6, lines 61—64).

Claim 17 is rejected under the same rationale set forth above to claim 13.

Claim 18 is rejected under the same rationale set forth above to claim 13.

Claim 19 is rejected under the same rationale set forth above to claim 13.

Claim 20 is rejected under the same rationale set forth above to claim 13.

Claim 21 is rejected under the same rationale set forth above to claim 13.

Claim 22 is rejected under the same rationale set forth above to claim 13.

Claim 23 is rejected under the same rationale set forth above to claim 13.

Regarding to claim 24, Tsao discloses a method of fabricating an integrated circuit package, comprising providing a planar heat spreader 12 as set forth in col. 5, lines 40-46, and fig. 2;

However, Tsao does not disclose mounting a plurality of thinned semiconductor dice on to a planar surface of the heat spreader to form a plurality of conjoined

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microelecronic packages; and singulating plurality of conjoined microelectronic packages.

Kutlu discloses mounting a plurality of thinned semiconductor dice on to a planar surface of the heat spreader to form a plurality of conjoined microelectronic packages; and singulating plurality of conjoined microelectronic packages as set forth in col. 3, lines 15-46, and fig. 2.

It would have been obvious to one of ordinary skill in the art at the time the invention was made to mount a plurality of thinned semiconductor dice on to a planar surface of the heat spreader to form a plurality of conjoined microelectronic packages; and singulating plurality of conjoined microelectronic packages in order to reduce or eliminate die cracks (col. 2, line 14).

Claim 25 is rejected under the same rationale set forth above to claim 24.

Claim 26 is rejected under the same rationale set forth above to claim 24.

Claim 27 is rejected under the same rationale set forth above to claim 24.

Claim 29 is rejected under the same rationale set forth above to claim 24.

Claim 30 is rejected under the same rationale set forth above to claim 24.

Regarding to claim 31, Tsao discloses the method wherein the die has a thickness of no more than 100 μ m (col. 3, lines 55-60).

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Regarding to claim 32, Tsao discloses a method of fabricating an integrated circuit package, comprising mounting a thinned semiconductor die that has a thickness of no more than 100 µm as set forth in col. 3, lines 55-60.

However, Tsao does not teach the thinned semiconductor die on a planar surface of a heat spreader, and wherein mounting includes depositing a metallization layer on a back surface of the die.

Kutlu teaches a thinned semiconductor die on a planar surface of a heat spreader, and wherein mounting includes depositing a metallization layer on a back surface of the die.

It would have been obvious to one of ordinary skill in the art at the time the invention was made to form a thinned semiconductor die on a planar surface of a heat spreader, and wherein mounting includes depositing a metallization layer on a back surface of the die in order to reduce or eliminate die cracks (col. 2, line 14).

Claim 33 is rejected under the same rationale set forth above to claim 32.

Claim 34 is rejected under the same rationale set forth above to claim 32.

Claim 35 is rejected under the same rationale set forth above to claim 32.

Claim 36 is rejected under the same rationale set forth above to claim 32.

Claim 37 is rejected under the same rationale set forth above to claim 32.

Claim 38 is rejected under the same rationale set forth above to claim 32.

Claim 39 is rejected under the same rationale set forth above to claim 32.

Claim 40 is rejected under the same rationale set forth above to claim 32.

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Claim 41 is rejected under the same rationale set forth above to claim 32.

Claim 42 is rejected under the same rationale set forth above to claim 32.

Claim 43 is rejected under the same rationale set forth above to claim 32.

Claim 44 is rejected under the same rationale set forth above to claim 32.

Conclusion

Any inquiry concerning this communication on earlier communications from the examiner should be directed to Mai-Huong Tran, (571) 272-1796. The examiner can normally be reached on Monday-Thursday from 8:00 AM to 6:30 PM. The examiner's supervisor, David Nelms can be reached on (571) 272-1787.

The fax phone number for the organization where this application or proceeding is assigned is (703) 872-9306. Any inquiry of a general nature or relating to the status of this application or proceeding should be directed to the receptionist whose telephone number is (703) 308-0956.

Mai-Huong Tran

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